



11/7/2007

**PRODUCT RELIABILITY REPORT
FOR**

DS2156, A2 (8")

Maxim Integrated Products

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Prepared by:

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Conclusion:

The following qualification successfully meets the quality and reliability standards required of all Maxim products:

DS2156, B1

In addition, Maxim's continuous reliability monitor program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards. The current status of the reliability monitor program can be viewed at <http://www.maxim-ic.com/TechSupport/dsreliability.html>.

Device Description:

A description of this device can be found in the product data sheet. You can find the product data sheet at http://dbserv.maxim-ic.com/l_datasheet3.cfm.

Reliability Derating:

The Arrhenius model will be used to determine the acceleration factor for failure mechanisms that are temperature accelerated.

$$AfT = \exp((Ea/k) * (1/Tu - 1/Ts)) = tu/ts$$

AfT = Acceleration factor due to Temperature
tu = Time at use temperature (e.g. 55°C)
ts = Time at stress temperature (e.g. 125°C)
k = Boltzmann's Constant (8.617 x 10⁻⁵ eV/°K)
Tu = Temperature at Use (°K)
Ts = Temperature at Stress (°K)
Ea = Activation Energy (e.g. 0.7 ev)

The activation energy of the failure mechanism is derived from either internal studies or industry accepted standards, or activation energy of 0.7ev will be used whenever actual failure mechanisms or their activation energies are unknown. All deratings will be done from the stress ambient temperature to the use ambient temperature.

An exponential model will be used to determine the acceleration factor for failure mechanisms, which are voltage accelerated.

$$AfV = \exp(B * (Vs - Vu))$$

AfV = Acceleration factor due to Voltage
Vs = Stress Voltage (e.g. 7.0 volts)
Vu = Maximum Operating Voltage (e.g. 5.5 volts)
B = Constant related to failure mechanism type (e.g. 1.0, 2.4, 2.7, etc.)

The Constant, B, related to the failure mechanism is derived from either internal studies or industry accepted standards, or a B of 1.0 will be used whenever actual failure mechanisms or their B are unknown. All deratings will be done from the stress voltage to the maximum operating voltage. Failure rate data from the operating life test is reported using a Chi-Squared statistical model at the 60% or 90% confidence level (Cf).

The failure rate, Fr, is related to the acceleration during life test by:

$$Fr = X / (ts * AfV * AfT * N * 2)$$

X = Chi-Sq statistical upper limit
N = Life test sample size

Failure Rates are reported in FITs (Failures in Time) or MTTF (Mean Time To Failure). The FIT rate is related to MTTF by:

$$MTTF = 1/Fr$$

NOTE: MTTF is frequently used interchangeably with MTBF.

The calculated failure rate for this device/process is:

FAILURE RATE:	MTTF (YRS):	113156	FITS:	1.0
	DEVICE HOURS:	963000	FAILS:	0

Only data from Operating Life or similar stresses are used for this calculation.

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **B: 0** **Tu: 25 °C** **Vu: 5.5 Volts**

The reliability data follows. At the start of this data is the device information. The next section is the detailed reliability data for each stress. The reliability data section includes the latest data available and may contain some generic data. "*" after DATE CODE denotes specific product data and SEQ No. to identify specific line items in the report for comments when required.

Device Information:

Process: E35DD-2P4M, 0.35um, P2Cap, 75A,Ti/Tin M1,BPSG,No Zero Mask
 Passivation: TEOS Ox-Nit Passivation for E35D; Full BEOL at SA; PT only in Dallas
 Die Size: 380 x 261
 Number of Transistors: 0
 Interconnect: Aluminum / 0.5% Copper
 Gate Oxide Thickness: 120 Å

ELECTRICAL CHARACTERIZATION

DESCRIPTION	DATE CODE/SEQ	CONDITION	READPOINT	QTY	FAILS	FA#
ESD SENSITIVITY	0607 * 1	EOS/ESD S5.1 HBM 500 VOLTS	1 PUL'S	3	0	
ESD SENSITIVITY	0607 * 2	EOS/ESD S5.1 HBM 1000 VOLTS	1 PUL'S	3	0	
ESD SENSITIVITY	0607 * 3	EOS/ESD S5.1 HBM 2000 VOLTS	1 PUL'S	3	0	
ESD SENSITIVITY	0607 * 4	EOS/ESD S5.1 HBM 4000 VOLTS	1 PUL'S	3	0	
ESD SENSITIVITY	0607 * 5	EOS/ESD S5.1 HBM 8000 VOLTS	1 PUL'S	3	3	No FA
ESD SENSITIVITY	0702 * 1	EOS/ESD S5.1 HBM 500 VOLTS	1 PUL'S	3	0	
ESD SENSITIVITY	0702 * 2	EOS/ESD S5.1 HBM 1000 VOLTS	1 PUL'S	3	0	
ESD SENSITIVITY	0702 * 3	EOS/ESD S5.1 HBM 2000 VOLTS	1 PUL'S	3	0	
ESD SENSITIVITY	0702 * 4	EOS/ESD S5.1 HBM 4000 VOLTS	1 PUL'S	3	1	No FA
ESD SENSITIVITY	0702 * 5	EOS/ESD S5.1 HBM 8000 VOLTS	1 PUL'S	3	3	No FA
LATCH-UP	0702 * 6	JESD78, I-TEST 125C		6	0	
LATCH-UP	0702 * 7	JESD78, V-SUPPLY TEST 125C		6	0	
Total:					7	

OPERATING LIFE

DESCRIPTION	DATE CODE/SEQ	CONDITION	READPOINT	QTY	FAILS	FA#
HIGH TEMP OP LIFE	0532 * 1	125C, 3.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0550 * 1	125C, 3.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0607	125C, 3.6 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0617 * 5	125C, 3.5 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0617 * 2	125C, 3.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0629 * 2	125C, 3.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0635 * 2	125C, 3.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0640 * 5	125C, 3.5 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0640 * 5	125C, 3.5 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0640 * 5	125C, 3.5 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0642 * 2	125C, 3.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0701	125C, 3.6 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0702 * 2	125C, 3.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0709 * 2	125C, 3.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0712 * 2	125C, 3.5 VOLTS	1000 HRS	77	0	

Total: 0

FAILURE RATE: MTTF (YRS): 113156 FITS: 1.0
DEVICE HOURS: 963000 FAILS: 0